REMARKS

Applicants appreciate the indication that Claim 16 is allowable. By the above amendment, Applicant has accepted this allowable subject matter without prejudice or disclaimer. A Notice of Allowance is earnestly solicited.

Respectfully submitted,

OBLON, SPIVAK McCLELLAND,

MAIER & NEUSTADT, P.C.

Richard L. Treanor, Ph.D. Attorney of Record

Registration No. 36,379

22850

(703) 413-3000 RLT/cja

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Marked-Up Copy Serial No.: 09/766,046 Amendment Filed: Herewith

-1. (Amended) A semiconductor structure comprising: a monocrystalline substrate;

an amorphous layer formed on the substrate; and

a first monocrystalline nitride material layer overlying the amorphous layer and formed of at least one selected from the group [comprising] consisting of GaN, GaInN, AlGaN, SiN and AlN, wherein the first monocrystalline nitride material layer is formed by

nitridation of a first monocrystalline material layer selected from the group consisting of GaAs, GaInAs, AlGaAs, Si and AlAs, and wherein said first monocrystalline

material layer has a thickness in the range of from about 20 angstroms to about 50 angstroms.

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